

ABSTRACT

5 **SYSTEMS AND METHODS FOR FACILITATING TESTING OF PAD RECEIVERS OF INTEGRATED CIRCUITS**

 An integrated circuit IC is provided that is adapted to provide information
corresponding to the receiver setup time and/or the receiver hold time of pad of the
10 IC. A preferred IC (210) includes a first pad (216, 500) electrically communicating
with at least a portion of the IC. The first pad includes a first driver (506) and a first
receiver (514), with the first driver being configured to provide a first pad output
signal to a component external to the IC, and the first receiver being configured to
receive a first pad input signal from a component internal to the IC. The first receiver
15 also is configured to provide, to a component internal to the IC, a first receiver digital
output signal in response to the first pad input signal. A first test circuit (224, 530)
also is provided that is internal to the IC. The first test circuit is adapted to provide
information corresponding to the receiver setup time and/or the receiver hold time of
the first pad. Systems and methods also are provided.

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Figure 5A